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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Active
Number of LABs/CLBs	32200
Number of Logic Elements/Cells	412160
Total RAM Bits	32440320
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 100°C (TJ)
Package / Case	1924-BBGA, FCBGA
Supplier Device Package	1927-FCBGA (45x45)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xc7vx415t-2ffg1927i

Table 1: Absolute Maximum Ratings⁽¹⁾ (Cont'd)

Symbol	Description	Min	Max	Units
$V_{MGTAVTRCAL}$	Analog supply voltage for the resistor calibration circuit of the GTX/GTH transceiver column	-0.5	1.32	V
V_{IN}	Receiver (RXP/RXN) and Transmitter (TXP/TXN) absolute input voltage	-0.5	1.26	V
I_{DCIN}	DC input current for receiver input pins DC coupled $V_{MGTAVTT} = 1.2V$	-	14	mA
I_{DCOUT}	DC output current for transmitter pins DC coupled $V_{MGTAVTT} = 1.2V$	-	14	mA
XADC				
V_{CCADC}	XADC supply relative to GNDADC	-0.5	2.0	V
V_{REFP}	XADC reference input relative to GNDADC	-0.5	2.0	V
Temperature				
T_{STG}	Storage temperature (ambient)	-65	150	°C
T_{SOL}	Maximum soldering temperature for Pb/Sn component bodies ⁽⁶⁾	-	+220	°C
	Maximum soldering temperature for Pb-free component bodies ⁽⁶⁾	-	+260	°C
T_j	Maximum junction temperature ⁽⁶⁾	-	+125	°C

Notes:

- Stresses beyond those listed under Absolute Maximum Ratings might cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time might affect device reliability.
- The lower absolute voltage specification always applies.
- For I/O operation, refer to the 7 Series FPGAs SelectIO Resources User Guide ([UG471](#)).
- The maximum limit applies to DC signals. For maximum undershoot and overshoot AC specifications, see [Table 4](#) and [Table 5](#).
- See [Table 10](#) for TMDS_33 specifications.
- For soldering guidelines and thermal considerations, see the 7 Series FPGA Packaging and Pinout Specification ([UG475](#)).

Table 2: Recommended Operating Conditions⁽¹⁾⁽²⁾

Symbol	Description	Min	Typ	Max	Units
FPGA Logic					
$V_{CCINT}^{(3)}$	Internal supply voltage	0.97	1.00	1.03	V
	Internal supply voltage for -1C devices with voltage identification (VID) bit programmed to run at 0.9V typical ⁽⁴⁾ .	0.87	0.90	0.93	V
$V_{CCBRAM}^{(3)}$	Block RAM supply voltage	0.97	1.00	1.03	V
	Block RAM supply voltage for -1C devices with voltage identification (VID) bit programmed to run at 0.9V typical ⁽⁴⁾ .	0.87	0.90	1.03	V
V_{CCAUX}	Auxiliary supply voltage	1.71	1.80	1.89	V
$V_{CCO}^{(5)(6)}$	Supply voltage for 3.3V HR I/O banks	1.14	-	3.465	V
	Supply voltage for 1.8V HP I/O banks	1.14	-	1.89	V
V_{CCAUX_IO}	Auxiliary supply voltage when set to 1.8V	1.71	1.80	1.89	V
	Auxiliary supply voltage when set to 2.0V	1.94	2.00	2.06	V
$V_{IN}^{(7)}$	I/O input voltage	-0.20	-	$V_{CCO} + 0.2$	V
	I/O input voltage (when $V_{CCO} = 3.3V$) for V_{REF} and differential I/O standards except TMDS_33 ⁽⁸⁾	-0.20	-	2.625	V
$I_{IN}^{(9)}$	Maximum current through any pin in a powered or unpowered bank when forward biasing the clamp diode.	-	-	10	mA
$V_{CCBATT}^{(10)}$	Battery voltage	1.0	-	1.89	V

Table 5: V_{IN} Maximum Allowed AC Voltage Overshoot and Undershoot for 1.8V HP I/O Banks⁽¹⁾⁽²⁾

AC Voltage Overshoot	% of UI @-40°C to 100°C	AC Voltage Undershoot	% of UI @-40°C to 100°C
$V_{CCO} + 0.55$	100	-0.55	100
$V_{CCO} + 0.60$	50.0	-0.60	50.0
$V_{CCO} + 0.65$	50.0	-0.65	50.0
$V_{CCO} + 0.70$	47.0	-0.70	50.0
$V_{CCO} + 0.75$	21.2	-0.75	50.0
$V_{CCO} + 0.80$	9.71	-0.80	50.0
$V_{CCO} + 0.85$	4.51	-0.85	28.4
$V_{CCO} + 0.90$	2.12	-0.90	12.7
$V_{CCO} + 0.95$	1.01	-0.95	5.79

Notes:

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20 μ s.

Table 6: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade			Units
			-3	-2/-2L/-2G	-1	
I _{CCINTQ}	Quiescent V_{CCINT} supply current	XC7V585T	1483	1483	1483	mA
		XC7V2000T	N/A	3756	3756	mA
		XC7VX330T	1012	1012	1012	mA
		XC7VX415T	1324	1324	1324	mA
		XC7VX485T	1578	1578	1578	mA
		XC7VX550T	2214	2214	2214	mA
		XC7VX690T	2214	2214	2214	mA
		XC7VX980T	N/A	2580	2580	mA
		XC7VX1140T	N/A	3448	3448	mA
I _{CCOQ}	Quiescent V_{CCO} supply current	XC7V585T	1	1	1	mA
		XC7V2000T	N/A	1	1	mA
		XC7VX330T	1	1	1	mA
		XC7VX415T	1	1	1	mA
		XC7VX485T	1	1	1	mA
		XC7VX550T	1	1	1	mA
		XC7VX690T	1	1	1	mA
		XC7VX980T	N/A	1	1	mA
		XC7VX1140T	N/A	1	1	mA

Speed Grade Designations

Since individual family members are produced at different times, the migration from one category to another depends completely on the status of the fabrication process for each device. [Table 15](#) correlates the current status of each Virtex-7 T and XT device on a per speed grade basis.

[Table 15: Virtex-7 T and XT Device Speed Grade Designations](#)

Device	Speed Grade Designations		
	Advance	Preliminary	Production
XC7V585T			-3, -2, -2L, -1
XC7V2000T	-2L, -2G		-2, -1
XC7VX330T			-3, -2, -2L, -1
XC7VX415T			-3, -2, -2L, -1
XC7VX485T			-3, -2, -2L, -1
XC7VX550T			-3, -2, -2L, -1
XC7VX690T			-3, -2, -2L, -1
XC7VX980T	-2, -2L, -1		
XC7VX1140T	-2, -2L, -2G, -1		

Production Silicon and Software Status

In some cases, a particular family member (and speed grade) is released to production before a speed specification is released with the correct label (Advance, Preliminary, Production). Any labeling discrepancies are corrected in subsequent speed specification releases.

[Table 16](#) lists the production released Virtex-7 T and XT device, speed grade, and the minimum corresponding supported speed specification version and software revisions. The software and speed specifications listed are the minimum releases required for production. All subsequent releases of software and speed specifications are valid.

[Table 16: Virtex-7 T and XT Device Production Software and Speed Specification Release](#)

Device	Speed Grade Designations				
	-3	-2G	-2	-2L	-1
XC7V585T	Vivado 2012.4 v1.08 or ISE 14.2 v1.06	N/A	Vivado 2012.4 v1.08 or ISE 14.2 v1.06		
XC7V2000T	N/A		Vivado 2012.4 v1.07		Vivado 2012.4 v1.07
XC7VX330T	Vivado 2013.1 v1.08 or ISE 14.5 v1.08	N/A	Vivado 2013.1 v1.08 or ISE 14.5 v1.08		
XC7VX415T		N/A			
XC7VX485T	Vivado 2012.4 v1.08 or ISE 14.2 v1.06	N/A	Vivado 2012.4 v1.08 or ISE 14.2 v1.06		
XC7VX550T	Vivado 2013.1 v1.08 or ISE 14.5 v1.08	N/A	Vivado 2013.1 v1.08 or ISE 14.5 v1.08		
XC7VX690T	Vivado 2013.1 v1.08 or ISE 14.5 v1.08	N/A	Vivado 2013.1 v1.08 or ISE 14.5 v1.08		
XC7VX980T	N/A	N/A			
XC7VX1140T	N/A				

Notes:

- Blank entries indicate a device and/or speed grade in advance or preliminary status.

Performance Characteristics

This section provides the performance characteristics of some common functions and designs implemented in Virtex-7 T and XT devices. The numbers reported here are worst-case values; they have all been fully characterized. These values are subject to the same guidelines as the [AC Switching Characteristics, page 12](#). In each table, the I/O bank type is either High Performance (HP) or High Range (HR).

Table 17: Networking Applications Interface Performances

Description	I/O Bank Type	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
SDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 8)	HR	710	710	625	Mb/s
	HP	710	710	625	Mb/s
DDR LVDS transmitter (using OSERDES; DATA_WIDTH = 4 to 14)	HR	1250	1250	950	Mb/s
	HP	1600	1400	1250	Mb/s
SDR LVDS receiver (SFI-4.1) ⁽¹⁾	HR	710	710	625	Mb/s
	HP	710	710	625	Mb/s
DDR LVDS receiver (SPI-4.2) ⁽¹⁾	HR	1250	1250	950	Mb/s
	HP	1600	1400	1250	Mb/s

Notes:

1. LVDS receivers are typically bounded with certain applications where specific dynamic phase-alignment (DPA) algorithms dominate deterministic performance.

IOB Pad Input/Output/3-State

Table 19 (3.3V high-range IOB (HR)) and **Table 20** (1.8V high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- T_{IOPI} is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- T_{IOOP} is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- T_{IOTP} is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than T_{IOTP} when the DCITERMDISABLE pin is used. In HR I/O banks, the IN_TERM termination turn-on time is always faster than T_{IOTP} when the INTERMDISABLE pin is used.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	T_{IOPI}			T_{IOOP}			T_{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1		
LVTTL_S4	1.31	1.42	1.64	3.77	3.90	4.00	4.53	4.76	4.99	ns	
LVTTL_S8	1.31	1.42	1.64	3.50	3.64	3.73	4.26	4.50	4.72	ns	
LVTTL_S12	1.31	1.42	1.64	3.49	3.62	3.72	4.25	4.48	4.71	ns	
LVTTL_S16	1.31	1.42	1.64	3.03	3.17	3.26	3.79	4.03	4.25	ns	
LVTTL_S24	1.31	1.42	1.64	3.25	3.39	3.48	4.01	4.25	4.47	ns	
LVTTL_F4	1.31	1.42	1.64	3.22	3.36	3.45	3.98	4.22	4.44	ns	
LVTTL_F8	1.31	1.42	1.64	2.71	2.84	2.93	3.47	3.70	3.92	ns	
LVTTL_F12	1.31	1.42	1.64	2.69	2.82	2.92	3.45	3.68	3.91	ns	
LVTTL_F16	1.31	1.42	1.64	2.57	2.85	3.15	3.33	3.71	4.14	ns	
LVTTL_F24	1.31	1.42	1.64	2.41	2.64	2.89	3.17	3.50	3.88	ns	
LVDS_25 ⁽¹⁾	0.64	0.68	0.80	1.36	1.47	1.55	2.12	2.33	2.54	ns	
MINI_LVDS_25	0.68	0.70	0.79	1.36	1.47	1.55	2.12	2.33	2.54	ns	
BLVDS_25 ⁽¹⁾	0.65	0.69	0.80	1.83	2.02	2.20	2.59	2.88	3.19	ns	
RSDS_25 (point to point) ⁽¹⁾	0.63	0.68	0.79	1.36	1.48	1.55	2.12	2.34	2.54	ns	
PPDS_25 ⁽¹⁾	0.65	0.69	0.80	1.36	1.49	1.58	2.12	2.35	2.57	ns	
TMDS_33 ⁽¹⁾	0.72	0.76	0.86	1.43	1.54	1.60	2.19	2.40	2.59	ns	
PCI33_3 ⁽¹⁾	1.28	1.41	1.65	2.71	3.08	3.52	3.47	3.94	4.51	ns	
HSUL_12	0.63	0.64	0.71	1.77	1.90	2.00	2.53	2.76	2.99	ns	
DIFF_HSUL_12	0.58	0.61	0.70	1.55	1.68	1.78	2.31	2.54	2.77	ns	
HSTL_I_S	0.61	0.64	0.73	1.55	1.69	1.80	2.31	2.55	2.79	ns	
HSTL_II_S	0.61	0.64	0.73	1.21	1.34	1.43	1.97	2.20	2.42	ns	
HSTL_I_18_S	0.64	0.67	0.76	1.28	1.39	1.45	2.04	2.25	2.44	ns	
HSTL_II_18_S	0.64	0.67	0.76	1.18	1.31	1.40	1.94	2.17	2.39	ns	
DIFF_HSTL_I_S	0.63	0.67	0.77	1.42	1.54	1.61	2.18	2.40	2.60	ns	
DIFF_HSTL_II_S	0.63	0.67	0.77	1.15	1.24	1.27	1.91	2.10	2.26	ns	
DIFF_HSTL_I_18_S	0.65	0.69	0.78	1.27	1.38	1.43	2.03	2.24	2.42	ns	
DIFF_HSTL_II_18_S	0.65	0.69	0.78	1.14	1.23	1.26	1.90	2.09	2.25	ns	
HSTL_I_F	0.61	0.64	0.73	1.10	1.19	1.23	1.86	2.05	2.22	ns	

Table 20: 1.8V IOB High Performance (HP) Switching Characteristics (Cont'd)

I/O Standard	T _{IOPI}			T _{IOOP}			T _{IOTP}			Units	
	Speed Grade			Speed Grade			Speed Grade				
	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1	-3	-2/-2L/-2G	-1		
DIFF_HSTL_I_18_F	0.75	0.79	0.92	1.04	1.16	1.24	1.68	1.91	2.06	ns	
DIFF_HSTL_II_18_F	0.75	0.79	0.92	0.98	1.09	1.16	1.62	1.85	1.98	ns	
DIFF_HSTL_I_DCI_18_F	0.75	0.79	0.92	1.04	1.16	1.24	1.67	1.91	2.06	ns	
DIFF_HSTL_II_DCI_18_F	0.75	0.79	0.92	0.98	1.09	1.16	1.61	1.85	1.98	ns	
DIFF_HSTL_II_T_DCI_18_F	0.75	0.79	0.92	1.04	1.16	1.24	1.67	1.91	2.06	ns	
LVCMOS18_S2	0.47	0.50	0.60	3.95	4.28	4.85	4.59	5.04	5.67	ns	
LVCMOS18_S4	0.47	0.50	0.60	2.67	2.98	3.43	3.31	3.73	4.26	ns	
LVCMOS18_S6	0.47	0.50	0.60	2.14	2.38	2.72	2.77	3.14	3.54	ns	
LVCMOS18_S8	0.47	0.50	0.60	1.98	2.21	2.52	2.61	2.97	3.35	ns	
LVCMOS18_S12	0.47	0.50	0.60	1.70	1.91	2.17	2.34	2.67	2.99	ns	
LVCMOS18_S16	0.47	0.50	0.60	1.57	1.75	1.97	2.20	2.51	2.79	ns	
LVCMOS18_F2	0.47	0.50	0.60	3.50	3.87	4.48	4.14	4.63	5.30	ns	
LVCMOS18_F4	0.47	0.50	0.60	2.23	2.50	2.87	2.87	3.25	3.69	ns	
LVCMOS18_F6	0.47	0.50	0.60	1.80	2.00	2.26	2.43	2.76	3.08	ns	
LVCMOS18_F8	0.47	0.50	0.60	1.46	1.72	2.04	2.10	2.47	2.86	ns	
LVCMOS18_F12	0.47	0.50	0.60	1.26	1.40	1.53	1.89	2.16	2.35	ns	
LVCMOS18_F16	0.47	0.50	0.60	1.19	1.33	1.44	1.83	2.08	2.26	ns	
LVCMOS15_S2	0.59	0.62	0.73	3.55	3.89	4.45	4.19	4.65	5.27	ns	
LVCMOS15_S4	0.59	0.62	0.73	2.45	2.70	3.06	3.08	3.45	3.89	ns	
LVCMOS15_S6	0.59	0.62	0.73	2.24	2.51	2.88	2.88	3.26	3.71	ns	
LVCMOS15_S8	0.59	0.62	0.73	1.91	2.16	2.49	2.55	2.91	3.31	ns	
LVCMOS15_S12	0.59	0.62	0.73	1.77	1.98	2.23	2.41	2.73	3.05	ns	
LVCMOS15_S16	0.59	0.62	0.73	1.62	1.81	2.02	2.26	2.56	2.84	ns	
LVCMOS15_F2	0.59	0.62	0.73	3.38	3.69	4.18	4.02	4.44	5.00	ns	
LVCMOS15_F4	0.59	0.62	0.73	2.04	2.21	2.44	2.68	2.97	3.26	ns	
LVCMOS15_F6	0.59	0.62	0.73	1.47	1.74	2.09	2.10	2.50	2.91	ns	
LVCMOS15_F8	0.59	0.62	0.73	1.31	1.46	1.61	1.95	2.22	2.43	ns	
LVCMOS15_F12	0.59	0.62	0.73	1.21	1.34	1.45	1.84	2.10	2.27	ns	
LVCMOS15_F16	0.59	0.62	0.73	1.18	1.31	1.41	1.82	2.07	2.23	ns	
LVCMOS12_S2	0.64	0.67	0.78	3.38	3.80	4.48	4.02	4.55	5.30	ns	
LVCMOS12_S4	0.64	0.67	0.78	2.62	2.94	3.43	3.26	3.70	4.25	ns	
LVCMOS12_S6	0.64	0.67	0.78	2.05	2.33	2.72	2.69	3.08	3.54	ns	
LVCMOS12_S8	0.64	0.67	0.78	1.94	2.18	2.51	2.58	2.94	3.33	ns	
LVCMOS12_F2	0.64	0.67	0.78	2.84	3.15	3.62	3.48	3.90	4.44	ns	
LVCMOS12_F4	0.64	0.67	0.78	1.97	2.18	2.44	2.61	2.93	3.26	ns	
LVCMOS12_F6	0.64	0.67	0.78	1.33	1.51	1.70	1.96	2.26	2.52	ns	
LVCMOS12_F8	0.64	0.67	0.78	1.27	1.42	1.55	1.91	2.18	2.37	ns	
LVDCI_18	0.47	0.50	0.60	1.99	2.15	2.35	2.62	2.91	3.17	ns	

Input/Output Logic Switching Characteristics

Table 22: ILOGIC Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup/Hold					
T _{ICE1CK/T_{ICKCE1}}	CE1 pin setup/hold with respect to CLK	0.42/0.00	0.48/0.00	0.67/0.00	ns
T _{ISRCK/T_{ICKSR}}	SR pin setup/hold with respect to CLK	0.53/0.01	0.61/0.01	0.99/0.01	ns
T _{IDOCKE2/T_{IOCKDE2}}	D pin setup/hold with respect to CLK without delay (HP I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	ns
T _{IDOCKDE2/T_{IOCKDDE2}}	DDLY pin setup/hold with respect to CLK (using IDELAY) (HP I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	ns
T _{IDOCKE3/T_{IOCKDE3}}	D pin setup/hold with respect to CLK without delay (HR I/O banks only)	0.01/0.27	0.01/0.29	0.01/0.34	ns
T _{IDOCKDE3/T_{IOCKDDE3}}	DDLY pin setup/hold with respect to CLK (using IDELAY) (HR I/O banks only)	0.01/0.27	0.02/0.29	0.02/0.34	ns
Combinatorial					
T _{IDIE2}	D pin to O pin propagation delay, no delay (HP I/O banks only)	0.09	0.10	0.12	ns
T _{IDIDE2}	DDLY pin to O pin propagation delay (using IDELAY) (HP I/O banks only)	0.10	0.11	0.13	ns
T _{IDIE3}	D pin to O pin propagation delay, no delay (HR I/O banks only)	0.09	0.10	0.12	ns
T _{IDIDE3}	DDLY pin to O pin propagation delay (using IDELAY) (HR I/O banks only)	0.10	0.11	0.13	ns
Sequential Delays					
T _{IDLOE2}	D pin to Q1 pin using flip-flop as a latch without delay (HP I/O banks only)	0.36	0.39	0.45	ns
T _{IDLODE2}	DDLY pin to Q1 pin using flip-flop as a latch (using IDELAY) (HP I/O banks only)	0.36	0.39	0.45	ns
T _{IDLOE3}	D pin to Q1 pin using flip-flop as a latch without delay (HR I/O banks only)	0.36	0.39	0.45	ns
T _{IDLODE3}	DDLY pin to Q1 pin using flip-flop as a latch (using IDELAY) (HR I/O banks only)	0.36	0.39	0.45	ns
T _{ICKQ}	CLK to Q outputs	0.47	0.50	0.58	ns
T _{RQ_ILOGICE2}	SR pin to OQ/TQ out (HP I/O banks only)	0.84	0.94	1.16	ns
T _{GSRQ_ILOGICE2}	Global set/reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	ns
T _{RQ_ILOGICE3}	SR pin to OQ/TQ out (HR I/O banks only)	0.84	0.94	1.16	ns
T _{GSRQ_ILOGICE3}	Global set/reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	ns
Set/Reset					
T _{RPW_ILOGICE2}	Minimum pulse width, SR inputs (HP I/O banks only)	0.54	0.63	0.63	ns, Min
T _{RPW_ILOGICE3}	Minimum pulse width, SR inputs (HR I/O banks only)	0.54	0.63	0.63	ns, Min

Input Serializer/Deserializer Switching Characteristics

Table 24: ISERDES Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup/Hold for Control Lines					
T _{ISCKC_BITSILIP} /T _{ISCKC_BITSILIP}	BITSILIP pin setup/hold with respect to CLKDIV	0.01/0.12	0.02/0.13	0.02/0.15	ns
T _{ISCKC_CE} / T _{ISCKC_CE} ⁽²⁾	CE pin setup/hold with respect to CLK (for CE1)	0.39/-0.02	0.44/-0.02	0.63/-0.02	ns
T _{ISCKC_CE2} / T _{ISCKC_CE2} ⁽²⁾	CE pin setup/hold with respect to CLKDIV (for CE2)	-0.12/0.29	-0.12/0.31	-0.12/0.35	ns
Setup/Hold for Data Lines					
T _{ISDCK_D} / T _{ISCKD_D}	D pin setup/hold with respect to CLK	-0.02/0.11	-0.02/0.12	-0.02/0.15	ns
T _{ISDCK_DDLY} / T _{ISCKD_DDLY}	DDLY pin setup/hold with respect to CLK (using IDELAY) ⁽¹⁾	-0.02/0.11	-0.02/0.12	-0.02/0.15	ns
T _{ISDCK_D_DDR} / T _{ISCKD_D_DDR}	D pin setup/hold with respect to CLK at DDR mode	-0.02/0.11	-0.02/0.12	-0.02/0.15	ns
T _{ISDCK_DDLY_DDR} / T _{ISCKD_DDLY_DDR}	D pin setup/hold with respect to CLK at DDR mode (using IDELAY) ⁽¹⁾	0.11/0.11	0.12/0.12	0.15/0.15	ns
Sequential Delays					
T _{ISCKO_Q}	CLKDIV to out at Q pin	0.46	0.47	0.58	ns
Propagation Delays					
T _{ISDO_DO}	D input to DO output pin	0.09	0.10	0.12	ns

Notes:

1. Recorded at 0 tap value.
2. T_{ISCKC_CE2} and T_{ISCKC_CE2} are reported as T_{ISCKC_CE}/T_{ISCKC_CE} in the timing report.

Output Serializer/Deserializer Switching Characteristics

Table 25: OSERDES Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Setup/Hold					
T _{OSDCK_D} /T _{OSCKD_D}	D input setup/hold with respect to CLKDIV	0.37/0.02	0.40/0.02	0.55/0.02	ns
T _{OSDCK_T} /T _{OSCKD_T} ⁽¹⁾	T input setup/hold with respect to CLK	0.49/-0.15	0.56/-0.15	0.68/-0.15	ns
T _{OSDCK_T2} /T _{OSCKD_T2} ⁽¹⁾	T input setup/hold with respect to CLKDIV	0.27/-0.15	0.30/-0.15	0.34/-0.15	ns
T _{OSCCK_OCE} /T _{OSCKC_OCE}	OCE input setup/hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	ns
T _{OSCCK_S}	SR (Reset) input setup with respect to CLKDIV	0.41	0.46	0.75	ns
T _{OSCCK_TCE} /T _{OSCKC_TCE}	TCE input setup/hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	ns
Sequential Delays					
T _{OSCKO_OQ}	Clock to out from CLK to OQ	0.35	0.37	0.42	ns
T _{OSCKO_TQ}	Clock to out from CLK to TQ	0.41	0.43	0.49	ns
Combinatorial					
T _{OSDO_TTQ}	T input to TQ Out	0.73	0.81	0.97	ns

Notes:

1. T_{OSDCK_T2} and T_{OSCKD_T2} are reported as T_{OSDCK_T}/T_{OSCKD_T} in the timing report.

Table 27: IO_FIFO Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
IO_FIFO Clock to Out Delays					
T _{OFFCKO_DO}	RDCLK to Q outputs	0.51	0.56	0.63	ns
T _{CKO_FLAGS}	Clock to IO_FIFO flags	0.59	0.62	0.81	ns
Setup/Hold					
T _{CCK_D} /T _{CKC_D}	D inputs to WRCLK	0.43/-0.01	0.47/-0.01	0.53/-0.01	ns
T _{IFFCCK_WREN} /T _{IFFCKC_WREN}	WREN to WRCLK	0.39/-0.01	0.43/-0.01	0.50/-0.01	ns
T _{OFFCCK_RDEN} /T _{OFFCKC_RDEN}	RDEN to RDCLK	0.49/0.01	0.53/0.02	0.61/0.02	ns
Minimum Pulse Width					
T _{PWH_IO_FIFO}	RESET, RDCLK, WRCLK	0.81	0.92	1.08	ns
T _{PWL_IO_FIFO}	RESET, RDCLK, WRCLK	0.81	0.92	1.08	ns
Maximum Frequency					
F _{MAX}	RDCLK and WRCLK	533.05	470.37	400.00	MHz

CLB Switching Characteristics

Table 28: CLB Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Combinatorial Delays					
T _{ILO}	An – Dn LUT address to A	0.05	0.05	0.06	ns, Max
T _{ILO_2}	An – Dn LUT address to AMUX/CMUX	0.15	0.16	0.19	ns, Max
T _{ILO_3}	An – Dn LUT address to BMUX_A	0.24	0.25	0.30	ns, Max
T _{ITO}	An – Dn inputs to A – D Q outputs	0.58	0.61	0.74	ns, Max
T _{AXA}	AX inputs to AMUX output	0.38	0.40	0.49	ns, Max
T _{AXB}	AX inputs to BMUX output	0.40	0.42	0.52	ns, Max
T _{AXC}	AX inputs to CMUX output	0.39	0.41	0.50	ns, Max
T _{AXD}	AX inputs to DMUX output	0.43	0.44	0.52	ns, Max
T _{BXB}	BX inputs to BMUX output	0.31	0.33	0.40	ns, Max
T _{BXD}	BX inputs to DMUX output	0.38	0.39	0.47	ns, Max
T _{CXC}	CX inputs to CMUX output	0.27	0.28	0.34	ns, Max
T _{CXD}	CX inputs to DMUX output	0.33	0.34	0.41	ns, Max
T _{DXD}	DX inputs to DMUX output	0.32	0.33	0.40	ns, Max
Sequential Delays					
T _{CKO}	Clock to AQ – DQ outputs	0.26	0.27	0.32	ns, Max
T _{SHCKO}	Clock to AMUX – DMUX outputs	0.32	0.32	0.39	ns, Max
Setup and Hold Times of CLB Flip-Flops Before/After Clock CLK					
T _{AS/T_{AH}}	A _N – D _N input to CLK on A – D flip-flops	0.01/0.12	0.02/0.13	0.03/0.18	ns, Min
T _{DICK/T_{CKDI}}	A _X – D _X input to CLK on A – D flip-flops	0.04/0.14	0.04/0.14	0.05/0.20	ns, Min
	A _X – D _X input through MUXs and/or carry logic to CLK on A – D flip-flops	0.36/0.10	0.37/0.11	0.46/0.16	ns, Min
T _{CECK_CLB/T_{CKCE_CLB}}	CE input to CLK on A – D flip-flops	0.19/0.05	0.20/0.05	0.25/0.05	ns, Min
T _{SRCK/T_{CKSR}}	SR input to CLK on A – D flip-flops	0.30/0.05	0.31/0.07	0.37/0.09	ns, Min
Set/Reset					
T _{SRMIN}	SR input minimum pulse width	0.52	0.78	1.04	ns, Min
T _{RQ}	Delay from SR input to AQ – DQ flip-flops	0.38	0.38	0.46	ns, Max
T _{CEO}	Delay from CE input to AQ – DQ flip-flops	0.34	0.35	0.43	ns, Max
F _{TOG}	Toggle frequency (for export control)	1818	1818	1818	MHz

Block RAM and FIFO Switching Characteristics

Table 31: Block RAM and FIFO Switching Characteristics

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Block RAM and FIFO Clock-to-Out Delays					
T _{RCKO_DO} and T _{RCKO_DO_REG} ⁽¹⁾	Clock CLK to DOUT output (without output register) ⁽²⁾⁽³⁾	1.57	1.80	2.08	ns, Max
	Clock CLK to DOUT output (with output register) ⁽⁴⁾⁽⁵⁾	0.54	0.63	0.75	ns, Max
T _{RCKO_DO_ECC} and T _{RCKO_DO_ECC_REG}	Clock CLK to DOUT output with ECC (without output register) ⁽²⁾⁽³⁾	2.35	2.58	3.26	ns, Max
	Clock CLK to DOUT output with ECC (with output register) ⁽⁴⁾⁽⁵⁾	0.62	0.69	0.80	ns, Max
T _{RCKO_DO_CASCOUP} and T _{RCKO_DO_CASCOUP_REG}	Clock CLK to DOUT output with Cascade (without output register) ⁽²⁾	2.21	2.45	2.80	ns, Max
	Clock CLK to DOUT output with Cascade (with output register) ⁽⁴⁾	0.98	1.08	1.24	ns, Max
T _{RCKO_FLAGS}	Clock CLK to FIFO flags outputs ⁽⁶⁾	0.65	0.74	0.89	ns, Max
T _{RCKO_POINTERS}	Clock CLK to FIFO pointers outputs ⁽⁷⁾	0.79	0.87	0.98	ns, Max
T _{RCKO_PARITY_ECC}	Clock CLK to ECCPARITY in ECC encode only mode	0.66	0.72	0.80	ns, Max
T _{RCKO_SDBIT_ECC} and T _{RCKO_SDBIT_ECC_REG}	Clock CLK to BITERR (without output register)	2.17	2.38	3.01	ns, Max
	Clock CLK to BITERR (with output register)	0.57	0.65	0.76	ns, Max
T _{RCKO_RDADDR_ECC} and T _{RCKO_RDADDR_ECC_REG}	Clock CLK to RDADDR output with ECC (without output register)	0.64	0.74	0.90	ns, Max
	Clock CLK to RDADDR output with ECC (with output register)	0.71	0.79	0.92	ns, Max
Setup and Hold Times Before/After Clock CLK					
T _{RCKC_ADDRA} /T _{RCKC_ADDRA}	ADDR inputs ⁽⁸⁾	0.38/0.27	0.42/0.28	0.48/0.31	ns, Min
T _{RDCK_DI_WF_NC} / T _{RCKD_DI_WF_NC}	Data input setup/hold time when block RAM is configured in WRITE_FIRST or NO_CHANGE mode ⁽⁹⁾	0.49/0.51	0.55/0.53	0.63/0.57	ns, Min
T _{RDCK_DI_RF} /T _{RCKD_DI_RF}	Data input setup/hold time when block RAM is configured in READ_FIRST mode ⁽⁹⁾	0.17/0.25	0.19/0.29	0.21/0.35	ns, Min
T _{RDCK_DI_ECC} /T _{RCKD_DI_ECC}	DIN inputs with block RAM ECC in standard mode ⁽⁹⁾	0.42/0.37	0.47/0.39	0.53/0.43	ns, Min
T _{RDCK_DI_ECCW} /T _{RCKD_DI_ECCW}	DIN inputs with block RAM ECC encode only ⁽⁹⁾	0.79/0.37	0.87/0.39	0.99/0.43	ns, Min
T _{RDCK_DI_ECC_FIFO} / T _{RCKD_DI_ECC_FIFO}	DIN inputs with FIFO ECC in standard mode ⁽⁹⁾	0.89/0.47	0.98/0.50	1.12/0.54	ns, Min
T _{RCKC_INJECTBITERR} / T _{RCKC_INJECTBITERR}	Inject single/double bit error in ECC mode	0.49/0.30	0.55/0.31	0.63/0.34	ns, Min
T _{RCKC_EN} /T _{RCKC_EN}	Block RAM Enable (EN) input	0.30/0.17	0.33/0.18	0.38/0.20	ns, Min
T _{RCKC_REGCE} /T _{RCKC_REGCE}	CE input of output register	0.21/0.13	0.25/0.13	0.31/0.14	ns, Min
T _{RCKC_RSTREG} /T _{RCKC_RSTREG}	Synchronous RSTREG input	0.25/0.06	0.27/0.06	0.29/0.06	ns, Min
T _{RCKC_RSTRAM} /T _{RCKC_RSTRAM}	Synchronous RSTRAM input	0.27/0.35	0.29/0.37	0.31/0.39	ns, Min
T _{RCKC_WEA} /T _{RCKC_WEA}	Write Enable (WE) input (Block RAM only)	0.38/0.15	0.41/0.16	0.46/0.17	ns, Min
T _{RCKC_WREN} /T _{RCKC_WREN}	WREN FIFO inputs	0.39/0.25	0.39/0.30	0.40/0.37	ns, Min
T _{RCKC_RDEN} /T _{RCKC_RDEN}	RDEN FIFO inputs	0.36/0.26	0.36/0.30	0.37/0.37	ns, Min
Reset Delays					
T _{RCO_FLAGS}	Reset RST to FIFO flags/pointers ⁽¹⁰⁾	0.76	0.83	0.93	ns, Max
T _{RREC_RST} /T _{RREM_RST}	FIFO reset recovery and removal timing ⁽¹¹⁾	1.59/-0.68	1.76/-0.68	2.01/-0.68	ns, Max

Table 31: Block RAM and FIFO Switching Characteristics (Cont'd)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
Maximum Frequency					
F _{MAX_BRAM_WF_NC}	Block RAM (Write first and No change modes) When not in SDP RF mode	601.32	543.77	458.09	MHz
F _{MAX_BRAM_RF_PERFORMANCE}	Block RAM (Read first, Performance mode) When in SDP RF mode but no address overlap between port A and port B	601.32	543.77	458.09	MHz
F _{MAX_BRAM_RF_DELAYED_WRITE}	Block RAM (Read first, Delayed_write mode) When in SDP RF mode and there is possibility of overlap between port A and port B addresses	528.26	477.33	400.80	MHz
F _{MAX_CAS_WF_NC}	Block RAM Cascade (Write first, No change mode) When cascade but not in RF mode	551.27	493.83	408.00	MHz
F _{MAX_CAS_RF_PERFORMANCE}	Block RAM Cascade (Read first, Performance mode) When in cascade with RF mode and no possibility of address overlap/one port is disabled	551.27	493.83	408.00	MHz
F _{MAX_CAS_RF_DELAYED_WRITE}	When in cascade RF mode and there is a possibility of address overlap between port A and port B	478.24	427.35	350.88	MHz
F _{MAX_FIFO}	FIFO in all modes without ECC	601.32	543.77	458.09	MHz
F _{MAX_ECC}	Block RAM and FIFO in ECC configuration	484.26	430.85	351.12	MHz

Notes:

1. The timing report shows all of these parameters as T_{RCKO_DO}.
2. T_{RCKO_DOR} includes T_{RCKO_DOW}, T_{RCKO_DOPR}, and T_{RCKO_DOPW} as well as the B port equivalent timing parameters.
3. These parameters also apply to synchronous FIFO with DO_REG = 0.
4. T_{RCKO_DO} includes T_{RCKO_DOP} as well as the B port equivalent timing parameters.
5. These parameters also apply to multirate (asynchronous) and synchronous FIFO with DO_REG = 1.
6. T_{RCKO_FLAGS} includes the following parameters: T_{RCKO_AEMPTY}, T_{RCKO_AFULL}, T_{RCKO_EMPTY}, T_{RCKO_FULL}, T_{RCKO_RDERR}, T_{RCKO_WRERR}.
7. T_{RCKO_POINTERS} includes both T_{RCKO_RDCOUNT} and T_{RCKO_WRCOUNT}.
8. The ADDR setup and hold must be met when EN is asserted (even when WE is deasserted). Otherwise, block RAM data corruption is possible.
9. These parameters include both A and B inputs as well as the parity inputs of A and B.
10. T_{RCKO_FLAGS} includes the following flags: AEMPTY, AFULL, EMPTY, FULL, RDERR, WRERR, RDCOUNT, and WRCOUNT.
11. RDEN and WREN must be held Low prior to and during reset. The FIFO reset must be asserted for at least five positive clock edges of the slowest clock (WRCLK or RDCLK).

Clock Buffers and Networks

Table 33: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T _{BCCCK_CE} /T _{BCCKC_CE} ⁽¹⁾	CE pins setup/hold	0.12/0.30	0.14/0.38	0.26/0.38	ns
T _{BCCCK_S} /T _{BCCKC_S} ⁽¹⁾	S pins setup/hold	0.12/0.30	0.14/0.38	0.26/0.38	ns
T _{BCCKO_O} ⁽²⁾	BUFGCTRL delay from I0/I1 to O	0.08	0.10	0.12	ns
Maximum Frequency					
F _{MAX_BUFG}	Global clock tree (BUFG)	741.00	710.00	625.00	MHz

Notes:

1. T_{BCCCK_CE} and T_{BCCKC_CE} must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T_{BGCKO_O} (BUFG delay from I0 to O) values are the same as T_{BCCKO_O} values.

Table 34: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T _{BLOCKO_O}	Clock to out delay from I to O	1.04	1.14	1.32	ns
Maximum Frequency					
F _{MAX_BUFIO}	I/O clock tree (BUFIO)	800.00	800.00	710.00	MHz

Table 35: Regional Clock Buffer Switching Characteristics (BUFR)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T _{BRCKO_O}	Clock to out delay from I to O	0.60	0.65	0.77	ns
T _{BRCKO_O_BYP}	Clock to out delay from I to O with Divide Bypass attribute set	0.30	0.32	0.38	ns
T _{BRDO_O}	Propagation delay from CLR to O	0.71	0.75	0.96	ns
Maximum Frequency					
F _{MAX_BUFR} ⁽¹⁾	Regional clock tree (BUFR)	600.00	540.00	450.00	MHz

Notes:

1. The maximum input frequency to the BUFR and BUFMR is the BUFIO F_{MAX} frequency.

Table 36: Horizontal Clock Buffer Switching Characteristics (BUFH)

Symbol	Description	Speed Grade			Units
		-3	-2/-2L/-2G	-1	
T _{BHCKO_O}	BUFH delay from I to O	0.10	0.11	0.13	ns
T _{BHCKC_CE} /T _{BHCKC_CE}	CE pin setup and hold	0.20/0.16	0.23/0.20	0.38/0.21	ns
Maximum Frequency					
F _{MAX_BUFH}	Horizontal clock buffer (BUFH)	741.00	710.00	625.00	MHz

Table 55: GTX Transceiver Reference Clock Switching Characteristics

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
F_{GCLK}	Reference clock frequency range	-3 speed grade	60	—	700	MHz
		All other speed grades	60	—	670	MHz
T_{RCLK}	Reference clock rise time	20% – 80%	—	200	—	ps
T_{FCLK}	Reference clock fall time	80% – 20%	—	200	—	ps
T_{DCREF}	Reference clock duty cycle	Transceiver PLL only	40	50	60	%

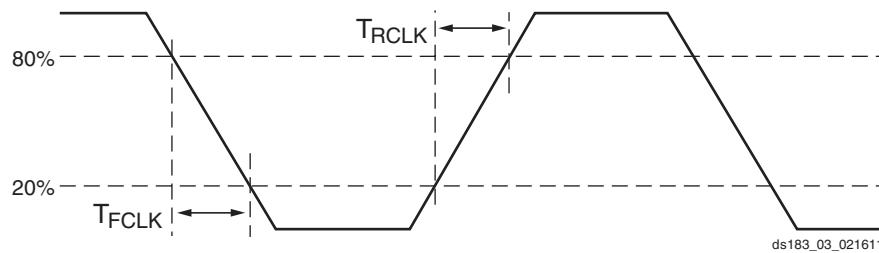


Figure 3: Reference Clock Timing Parameters

Table 56: GTX Transceiver PLL/Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T_{LOCK}	Initial PLL lock		—	—	1	ms
T_{DLOCK}	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	—	50,000	37×10^6	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		—	50,000	2.3×10^6	UI

Table 58: GTX Transceiver Transmitter Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
TJ _{6.6_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	6.6 Gb/s	—	—	0.30	UI
DJ _{6.6_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{5.0}	Total jitter ⁽³⁾⁽⁴⁾	5.0 Gb/s	—	—	0.30	UI
DJ _{5.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{4.25}	Total jitter ⁽³⁾⁽⁴⁾	4.25 Gb/s	—	—	0.30	UI
DJ _{4.25}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{3.75}	Total jitter ⁽³⁾⁽⁴⁾	3.75 Gb/s	—	—	0.30	UI
DJ _{3.75}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{3.20}	Total jitter ⁽³⁾⁽⁴⁾	3.20 Gb/s ⁽⁵⁾	—	—	0.20	UI
DJ _{3.20}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.10	UI
TJ _{3.20L}	Total jitter ⁽³⁾⁽⁴⁾	3.20 Gb/s ⁽⁶⁾	—	—	0.32	UI
DJ _{3.20L}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.16	UI
TJ _{2.5}	Total jitter ⁽³⁾⁽⁴⁾	2.5 Gb/s ⁽⁷⁾	—	—	0.20	UI
DJ _{2.5}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.08	UI
TJ _{1.25}	Total jitter ⁽³⁾⁽⁴⁾	1.25 Gb/s ⁽⁸⁾	—	—	0.15	UI
DJ _{1.25}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.06	UI
TJ ₅₀₀	Total jitter ⁽³⁾⁽⁴⁾	500 Mb/s	—	—	0.10	UI
DJ ₅₀₀	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.03	UI

Notes:

1. Using same REFCLK input with TX phase alignment enabled for up to 12 consecutive transmitters (three fully populated GTX Quads).
2. Using QPLL_FBDIV = 40, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. Using CPLL_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
4. All jitter values are based on a bit-error ratio of 1e⁻¹².
5. CPLL frequency at 3.2 GHz and TXOUT_DIV = 2.
6. CPLL frequency at 1.6 GHz and TXOUT_DIV = 1.
7. CPLL frequency at 2.5 GHz and TXOUT_DIV = 2.
8. CPLL frequency at 2.5 GHz and TXOUT_DIV = 4.

Table 59: GTX Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F_{GTXRX}	Serial data rate	RX oversampler not enabled	0.500	—	F_{GTXMAX}	Gb/s
$T_{RXELECIDLE}$	Time for RXELECIDLE to respond to loss or restoration of data		—	10	—	ns
RX_{OOBVDP}	OOB detect threshold peak-to-peak		60	—	150	mV
RX_{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	-5000	—	0	ppm
RX_{RL}	Run length (CID)		—	—	512	UI
RX_{PPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	-1250	—	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	-700	—	700	ppm
		Bit rates > 8.0 Gb/s	-200	—	200	ppm
SJ Jitter Tolerance⁽²⁾						
$JT_{SJ12.5}$	Sinusoidal jitter (QPLL) ⁽³⁾	12.5 Gb/s	0.3	—	—	UI
$JT_{SJ11.18}$	Sinusoidal jitter (QPLL) ⁽³⁾	11.18 Gb/s	0.3	—	—	UI
$JT_{SJ10.32}$	Sinusoidal jitter (QPLL) ⁽³⁾	10.32 Gb/s	0.3	—	—	UI
$JT_{SJ9.95}$	Sinusoidal jitter (QPLL) ⁽³⁾	9.95 Gb/s	0.3	—	—	UI
$JT_{SJ9.8}$	Sinusoidal jitter (QPLL) ⁽³⁾	9.8 Gb/s	0.3	—	—	UI
$JT_{SJ8.0}$	Sinusoidal jitter (QPLL) ⁽³⁾	8.0 Gb/s	0.44	—	—	UI
$JT_{SJ6.6_QPLL}$	Sinusoidal jitter (QPLL) ⁽³⁾	6.6 Gb/s	0.48	—	—	UI
$JT_{SJ6.6_CPLL}$	Sinusoidal jitter (CPLL) ⁽³⁾	6.6 Gb/s	0.44	—	—	UI
$JT_{SJ5.0}$	Sinusoidal jitter (CPLL) ⁽³⁾	5.0 Gb/s	0.44	—	—	UI
$JT_{SJ4.25}$	Sinusoidal jitter (CPLL) ⁽³⁾	4.25 Gb/s	0.44	—	—	UI
$JT_{SJ3.75}$	Sinusoidal jitter (CPLL) ⁽³⁾	3.75 Gb/s	0.44	—	—	UI
$JT_{SJ3.2}$	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	—	—	UI
$JT_{SJ3.2L}$	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁵⁾	0.45	—	—	UI
$JT_{SJ2.5}$	Sinusoidal jitter (CPLL) ⁽³⁾	2.5 Gb/s ⁽⁶⁾	0.5	—	—	UI
$JT_{SJ1.25}$	Sinusoidal jitter (CPLL) ⁽³⁾	1.25 Gb/s ⁽⁷⁾	0.5	—	—	UI
JT_{SJ500}	Sinusoidal jitter (CPLL) ⁽³⁾	500 Mb/s	0.4	—	—	UI
SJ Jitter Tolerance with Stressed Eye⁽²⁾						
$JT_{TJSE3.2}$	Total jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.70	—	—	UI
$JT_{TJSE6.6}$		6.6 Gb/s	0.70	—	—	UI
$JT_{SJSE3.2}$	Sinusoidal jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.1	—	—	UI
$JT_{SJSE6.6}$		6.6 Gb/s	0.1	—	—	UI

Notes:

1. Using RXOUT_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
5. CPLL frequency at 1.6 GHz and RXOUT_DIV = 1.
6. CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
7. CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
8. Composite jitter with RX equalizer enabled. DFE disabled.

Table 72: GTH Transceiver User Clock Switching Characteristics⁽¹⁾

Symbol	Description	Data Width Conditions		Speed Grade			Units
		Internal Logic	Interconnect Logic	-3E/-2GE ⁽²⁾	-2(C&I)/-2LE ⁽²⁾	-1(C&I) ⁽³⁾	
F _{TXOUT}	TXUSERCLKOUT maximum frequency			412.500	412.500	312.500	MHz
F _{RXOUT}	RXUSERCLKOUT maximum frequency			412.500	412.500	312.500	MHz
F _{TXIN}	TXUSERCLKIN maximum frequency	16-bit	16-bit and 32-bit	412.500	412.500	312.500	MHz
		32-bit	32-bit	409.375	353.125	265.625	MHz
F _{RXIN}	RXUSERCLKIN maximum frequency	16-bit	16-bit and 32-bit	412.500	412.500	312.500	MHz
		32-bit	32-bit	409.375	353.125	265.625	MHz
F _{TXIN2}	TXUSERCLKIN2 maximum frequency	16-bit	16-bit	412.500	412.500	312.500	MHz
		16-bit and 32-bit	32-bit	409.375	353.125	265.625	MHz
		64-bit	64-bit	204.688	176.563	132.813	MHz
F _{RXIN2}	RXUSERCLKIN2 maximum frequency	16-bit	16-bit	412.500	412.500	312.500	MHz
		16-bit and 32-bit	32-bit	409.375	353.125	265.625	MHz
		64-bit	64-bit	204.688	176.563	132.813	MHz

Notes:

- Clocking must be implemented as described in the 7 Series FPGAs GTX/GTH Transceiver User Guide ([UG476](#)).
- For speed grades -3E, -2GE, -2C, -2L, and -2LE, a 16-bit data path can only be used for speeds less than 6.6 Gb/s.
- For speed grade -1 (and when V_{CCINT} = 0.9V), a 16-bit data path can only be used for speeds less than 5.0 Gb/s.

Table 73: GTH Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F _{GTHTX}	Serial data rate range		0.500	–	F _{GTHMAX}	Gb/s
T _{RTX}	TX rise time	20%–80%	–	40	–	ps
T _{FTX}	TX fall time	80%–20%	–	40	–	ps
T _{LLSKEW}	TX lane-to-lane skew ⁽¹⁾		–	–	500	ps
V _{TXOOBVDP}	Electrical idle amplitude		–	–	15	mV
T _{TXOOBTRANSITION}	Electrical idle transition time		–	–	140	ns
TJ _{13.1}	Total jitter ⁽²⁾⁽⁴⁾	13.1 Gb/s	–	–	0.3	UI
DJ _{13.1}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{12.5}	Total jitter ⁽²⁾⁽⁴⁾	12.5 Gb/s	–	–	0.28	UI
DJ _{12.5}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{11.3}	Total jitter ⁽²⁾⁽⁴⁾	11.3 Gb/s	–	–	0.28	UI
DJ _{11.3}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{10.3125_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	10.3125 Gb/s	–	–	0.28	UI
DJ _{10.3125_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{10.3125_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	10.3125 Gb/s	–	–	0.33	UI
DJ _{10.3125_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		–	–	0.17	UI
TJ _{9.953}	Total jitter ⁽²⁾⁽⁴⁾	9.953 Gb/s	–	–	0.28	UI
DJ _{9.953}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{9.8}	Total jitter ⁽²⁾⁽⁴⁾	9.8 Gb/s	–	–	0.28	UI
DJ _{9.8}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI
TJ _{8.0_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	8.0 Gb/s	–	–	0.28	UI
DJ _{8.0_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		–	–	0.17	UI

Table 73: GTH Transceiver Transmitter Switching Characteristics (Cont'd)

Symbol	Description	Condition	Min	Typ	Max	Units
TJ _{8.0_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	8.0 Gb/s	—	—	0.32	UI
DJ _{8.0_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.17	UI
TJ _{6.6_QPLL}	Total jitter ⁽²⁾⁽⁴⁾	6.6 Gb/s	—	—	0.28	UI
DJ _{6.6_QPLL}	Deterministic jitter ⁽²⁾⁽⁴⁾		—	—	0.17	UI
TJ _{6.6_CPLL}	Total jitter ⁽³⁾⁽⁴⁾	6.6 Gb/s	—	—	0.30	UI
DJ _{6.6_CPLL}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{5.0}	Total jitter ⁽³⁾⁽⁴⁾	5.0 Gb/s	—	—	0.30	UI
DJ _{5.0}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{4.25}	Total jitter ⁽³⁾⁽⁴⁾	4.25 Gb/s	—	—	0.30	UI
DJ _{4.25}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{3.75}	Total jitter ⁽³⁾⁽⁴⁾	3.75 Gb/s	—	—	0.30	UI
DJ _{3.75}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.15	UI
TJ _{3.20}	Total jitter ⁽³⁾⁽⁴⁾	3.20 Gb/s ⁽⁵⁾	—	—	0.2	UI
DJ _{3.20}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.1	UI
TJ _{3.20L}	Total jitter ⁽³⁾⁽⁴⁾	3.20 Gb/s ⁽⁶⁾	—	—	0.32	UI
DJ _{3.20L}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.16	UI
TJ _{2.5}	Total jitter ⁽³⁾⁽⁴⁾	2.5 Gb/s ⁽⁷⁾	—	—	0.20	UI
DJ _{2.5}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.08	UI
TJ _{1.25}	Total jitter ⁽³⁾⁽⁴⁾	1.25 Gb/s ⁽⁸⁾	—	—	0.15	UI
DJ _{1.25}	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.06	UI
TJ ₅₀₀	Total jitter ⁽³⁾⁽⁴⁾	500 Mb/s	—	—	0.1	UI
DJ ₅₀₀	Deterministic jitter ⁽³⁾⁽⁴⁾		—	—	0.03	UI

Notes:

1. Using same REFCLK input with TX phase alignment enabled for up to 12 consecutive transmitters (three fully populated GTH Quads).
2. Using QPLL_FBDIV = 40, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
3. Using CPLL_FBDIV = 2, 20-bit internal data width. These values are NOT intended for protocol specific compliance determinations.
4. All jitter values are based on a bit-error ratio of $1e^{-12}$.
5. CPLL frequency at 3.2 GHz and TXOUT_DIV = 2.
6. CPLL frequency at 1.6 GHz and TXOUT_DIV = 1.
7. CPLL frequency at 2.5 GHz and TXOUT_DIV = 2.
8. CPLL frequency at 2.5 GHz and TXOUT_DIV = 4.

Table 74: GTH Transceiver Receiver Switching Characteristics

Symbol	Description		Min	Typ	Max	Units
F _{GTHRX}	Serial data rate	RX oversampler not enabled	0.500	—	F _{GTHMAX}	Gb/s
T _{RXELECIDLE}	Time for RXELECIDLE to respond to loss or restoration of data		—	10	—	ns
RX _{OOBVDP}	OOB detect threshold peak-to-peak		60	—	150	mV
RX _{SST}	Receiver spread-spectrum tracking ⁽¹⁾	Modulated @ 33 KHz	-5000	—	0	ppm
RX _{RL}	Run length (CID)		—	—	512	UI
RX _{PPMTOL}	Data/REFCLK PPM offset tolerance	Bit rates ≤ 6.6 Gb/s	-1250	—	1250	ppm
		Bit rates > 6.6 Gb/s and ≤ 8.0 Gb/s	-700	—	700	ppm
		Bit rates > 8.0 Gb/s	-200	—	200	ppm
SJ Jitter Tolerance⁽²⁾						
JT_SJ _{13.1}	Sinusoidal jitter (QPLL) ⁽³⁾	13.1 Gb/s	0.3	—	—	UI
JT_SJ _{12.5}	Sinusoidal jitter (QPLL) ⁽³⁾	12.5 Gb/s	0.3	—	—	UI
JT_SJ _{11.3}	Sinusoidal jitter (QPLL) ⁽³⁾	11.3 Gb/s	0.3	—	—	UI
JT_SJ _{10.32_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	10.32 Gb/s	0.3	—	—	UI
JT_SJ _{10.32_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	10.32 Gb/s	0.3	—	—	UI
JT_SJ _{9.8}	Sinusoidal jitter (QPLL) ⁽³⁾	9.8 Gb/s	0.3	—	—	UI
JT_SJ _{8.0_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	8.0 Gb/s	0.44	—	—	UI
JT_SJ _{8.0_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	8.0 Gb/s	0.42	—	—	UI
JT_SJ _{6.6_QPLL}	Sinusoidal jitter (QPLL) ⁽³⁾	6.6 Gb/s	0.48	—	—	UI
JT_SJ _{6.6_CPLL}	Sinusoidal jitter (CPLL) ⁽³⁾	6.6 Gb/s	0.44	—	—	UI
JT_SJ _{5.0}	Sinusoidal jitter (CPLL) ⁽³⁾	5.0 Gb/s	0.44	—	—	UI
JT_SJ _{4.25}	Sinusoidal jitter (CPLL) ⁽³⁾	4.25 Gb/s	0.44	—	—	UI
JT_SJ _{3.75}	Sinusoidal jitter (CPLL) ⁽³⁾	3.75 Gb/s	0.44	—	—	UI
JT_SJ _{3.2}	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁴⁾	0.45	—	—	UI
JT_SJ _{3.2L}	Sinusoidal jitter (CPLL) ⁽³⁾	3.2 Gb/s ⁽⁵⁾	0.45	—	—	UI
JT_SJ _{2.5}	Sinusoidal jitter (CPLL) ⁽³⁾	2.5 Gb/s ⁽⁶⁾	0.5	—	—	UI
JT_SJ _{1.25}	Sinusoidal jitter (CPLL) ⁽³⁾	1.25 Gb/s ⁽⁷⁾	0.5	—	—	UI
JT_SJ ₅₀₀	Sinusoidal jitter (CPLL) ⁽³⁾	500 Mb/s	0.4	—	—	UI
SJ Jitter Tolerance with Stressed Eye⁽²⁾						
JT_TJSE _{3.2}	Total jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.70	—	—	UI
JT_TJSE _{6.6}		6.6 Gb/s	0.70	—	—	UI
JT_SJSE _{3.2}	Sinusoidal jitter with stressed eye ⁽⁸⁾	3.2 Gb/s	0.1	—	—	UI
JT_SJSE _{6.6}		6.6 Gb/s	0.1	—	—	UI

Notes:

1. Using RXOUT_DIV = 1, 2, and 4.
2. All jitter values are based on a bit error ratio of $1e^{-12}$.
3. The frequency of the injected sinusoidal jitter is 80 MHz.
4. CPLL frequency at 3.2 GHz and RXOUT_DIV = 2.
5. CPLL frequency at 1.6 GHz and RXOUT_DIV = 1.
6. CPLL frequency at 2.5 GHz and RXOUT_DIV = 2.
7. CPLL frequency at 2.5 GHz and RXOUT_DIV = 4.
8. Composite jitter with RX equalizer enabled. DFE disabled.